

Chapter 2: Naturally distributions in combinational circuit theory

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1 Formulating Distributions in circuit theory

Any circuit function, can be writtern,in sums of products as in,

$$\sum_k \prod_i Y_i \quad (1)$$

where Y_i is either X_i or $1 - X_i$. Given that X_i are input probabilities , each term $\prod_i Y_i$ contributes to the probability. Now, instead of having a large function, it is possible,to work with it, statistically. Later on, we will go into issues, where this representation, fails and,what can be done to circumvent to rescue it.

Take $\prod_i Y_i$. Now, if you take the log of it.

$$\log \prod_i Y_i = \sum_i \log Y_i \quad (2)$$

As said earlier, Y_i will either be X_i or $1 - X_i$. And thus, $\log \prod_i Y_i$ behaves like a gaussian variable. As with most gaussian phenomenon, things of most interest are the mean and the standard deviation.

Let $\langle lt \rangle$ be the mean of log of the terms. And let σ_{lt} be the standard deviation of log of the terms. Suppose, y is a probability value contributed by a term, then probability of finding a term, that supplies y is given by

$$p(y, \langle lt \rangle, \sigma_{lt}) = \frac{1}{\sqrt{2\pi}\sigma_{lt}y} \exp \left(-\frac{(\log(y) - \langle lt \rangle)^2}{2\sigma_{lt}^2} \right) \quad (3)$$

The problem with this distribution, is that it assumes that the distribution is continous and this assumption has problems, of its own, which we will discuss later. We will fix that assumption, by putting a unit step function in there.

$$p(y, \langle lt \rangle, \sigma_{lt}, y_{max}, y_{min}) = \frac{1}{\sqrt{2\pi}\sigma_{lt}y} \exp\left(-\frac{(\log(y) - \langle lt \rangle)^2}{2\sigma_{lt}^2}\right) [u(y_{max} - y) - u(y_{min} - y)] \quad (4)$$

y_{max} is the value of the term that supplies the maximum individual probability and y_{min} is the value of the term that supplies the least individual probability. Suppose, N is the number of terms in the circuit, then,

$$\int_0^1 dy N \cdot y \cdot p(y, \langle lt \rangle, \sigma_{lt}, y_{max}, y_{min}) \quad (5)$$

would give the expected value of the output. Now, suppose, we decide to rewrite the above integration. Let $x = -\log y$. Then $y = \exp(-x)$ and $dx = -dy/y$, then $\exp(-x)dx = -dy$. Now,

$$\int_{-\infty}^0 dx N [-\exp(-x)] \frac{1}{\sqrt{2\pi}\sigma_{lt}} \exp\left(-\frac{(x - \langle lt \rangle)^2}{2\sigma_{lt}^2}\right) [u(x - -\log y_{max}) - u(x - -\log y_{min})] \quad (6)$$

Now, with a little bit of rearrangement, it becomes,

$$\int_0^{\infty} dx N \exp(-x) \frac{1}{\sqrt{2\pi}\sigma_{lt}} \exp\left(-\frac{(x - \langle lt \rangle)^2}{2\sigma_{lt}^2}\right) [u(x - -\log y_{max}) - u(x - -\log y_{min})] \quad (7)$$

which is the laplace transform of the gaussian, with s set to 1. We shall generalize the above expression as follows

$$\int_0^{\infty} dx N \exp(-s \cdot x) \frac{1}{\sqrt{2\pi}\sigma_{lt}} \exp\left(-\frac{(x - \langle lt \rangle)^2}{2\sigma_{lt}^2}\right) u(x - c) \quad (8)$$

$$(9)$$

for $c \geq 0$, it gives

$$\int_c^{\infty} dx N \exp(-s \cdot x) \frac{1}{\sqrt{2\pi}\sigma_{lt}} \exp\left(-\frac{(x - \langle lt \rangle)^2}{2\sigma_{lt}^2}\right) \quad (10)$$

Integrating with Maple or Mathematica, we get

$$\frac{N}{2} \exp\left(-\langle lt \rangle s + \frac{\sigma_{lt}^2 s^2}{2}\right) \operatorname{erfc}\left(\frac{-\langle lt \rangle + \sigma_{lt}^2 s + c}{\sqrt{2}\sigma_{lt}}\right) \quad (11)$$

We define

$$\Gamma(s, c, \langle lt \rangle, \sigma_{lt}) = \frac{1}{2} \exp\left(-\langle lt \rangle s + \frac{\sigma_{lt}^2 s^2}{2}\right) \operatorname{erfc}\left(\frac{-\langle lt \rangle + \sigma_{lt}^2 s + c}{\sqrt{2}\sigma_{lt}}\right) \quad (12)$$

2 Properties

Now, $N\Gamma(s, c, \langle lt \rangle, \sigma_{lt})$ is the probability of output being a 1. Now, $N^2\Gamma^2(s, c, \langle lt \rangle, \sigma_{lt})$ is the probability of the output being a 1, consecutively. Now, $N^k\Gamma^k(s, c, \langle lt \rangle, \sigma_{lt})$ is the probability that the function is a 1, in k consecutive runs.

It is interesting to see that in the following light. $E[C(\mathbf{X})]$ is the expected value of the function $C(\mathbf{X})$ with n independent inputs. Then, $E[C(\mathbf{X})]E[C(\mathbf{X})]$, is equivalent to the expected value of a function with $2n$ independent inputs. To see this explicitly, note the following.

$$\log \prod_i Y_i = \sum_i \log Y_i \quad (13)$$

Now, multiplication of the circuit, by itself, constitutes,

$$\log \prod_i^{2n} Y_{\text{new } i} = \sum_i^{2n} \log Y_{\text{new } i} \quad (14)$$

Now, after i goes pass n , the properties of Y_0, Y_1 , etc, repeat. So, the sum becomes

$$\log \prod_i^{2n} Y_{\text{new } i} = \sum_i^n \log Y_i + \sum_i^n \log Y'_i \quad (15)$$

Now, Y'_i is used to denote that, although they do have the same properties as Y_i , they are statistically independent.

More importantly, the new addition of n -input, changes the function, in such a way that $\langle lt \rangle$ and c increases two folds, and σ_{lt}^2 also increases two folds.

To see why c increases two folds. Remember that $c = \log(\max_{term})$.

$$\max \log \prod_i^{2n} Y_{\text{new } i} = \max \sum_i^n \log Y_i + \max \sum_i^n \log Y'_i \quad (16)$$

\max of $\log Y'_i$ has to be atleast as maximum as $\max \log Y_i$. Otherwise, it would not be a maximum, since Y_i s and Y'_i all have the same properties.

Generally, suppose if we take $E[C(\mathbf{X})]^k$, $\langle lt \rangle$, c and σ_{lt}^2 increase k -fold.

3 $\langle lt \rangle$ and σ_{lt}

Now, to compute, $\langle lt \rangle$ and σ_{lt} , assuming independence of terms involving x_i with terms involving x_j . We use the following lemmas

Lemma 1 *Given, independent variables, y_1, y_2, \dots, y_n , we have,*

$$\langle \sum_i y_i \rangle = \sum_i \langle y_i \rangle \quad (17)$$

$$\text{Var}(\sum_i y_i) = \sum_i \text{Var}(y_i) \quad (18)$$

Using the condition of independence, and the above lemma, we can prove the following

$$\langle lt \rangle = \sum_i -w_i \log(x_i) - (1 - w_i) \log(1 - x_i) \quad (19)$$

where w_i is the probability that a term involve x_i , as opposed to $1 - x_i$. Then, $1 - w_i$, is the probability that the term involves $1 - x_i$. Now, to compute the standard deviation of log of the terms, we just simply take

$$\sigma_{lt}^2 = \sum_i w_i \log^2(x_i) + (1 - w_i) \log^2(1 - x_i) - \sum_i (-w_i \log(x_i) - (1 - w_i) \log(1 - x_i))^2 \quad (20)$$

$$= \sum_i w_i \log^2(x_i) + (1 - w_i) \log^2(1 - x_i) - \quad (21)$$

$$\sum_i w_i^2 \log^2(x_i) + (1 - w_i)^2 \log^2(1 - x_i) - 2w_i(1 - w_i) \log(1 - x_i) \log(x_i) \quad (22)$$

$$= \sum_i (w_i - w_i^2) \log^2(x_i) + [(1 - w_i) - (1 - w_i)^2] \log^2(1 - x_i) \quad (23)$$

$$- 2w_i(1 - w_i) \log(1 - x_i) \log(x_i) \quad (24)$$

$$= \sum_i (w_i - w_i^2) \log^2(x_i) + (-w_i + 2w_i - w_i^2) \log^2(1 - x_i) - 2w_i(1 - w_i) \log(1 - x_i) \log(x_i) \quad (25)$$

$$= \sum_i (w_i - w_i^2) \log^2(x_i) + (w_i - w_i^2) \log^2(1 - x_i) - 2w_i(1 - w_i) \log(1 - x_i) \log(x_i) \quad (26)$$

$$= \sum_i w_i(1 - w_i) (\log(x_i) - \log(1 - x_i))^2 \quad (27)$$

For a given circuit, w_i , remain unchanged, even when input probabilities change. So, now, if we reformulate, our fault distribution, in language of w_i s. It should be noted that, the above relationship, will still hold, if we replace w_i with an arbitrary a_i and $1 - w_i$ with b_i . To see this, suppose, we multiply the w_i and $1 - w_i$ by c_i , we would have $c_i w_i \log(x_i) + c_i(1 - w_i) \log(1 - x_i)$ and we would have $c^2 w_i(1 - w_i) (\log(x_i) - \log(1 - x_i))^2$. So, if $a_i = c w_i$ and $b_i = c(1 - w_i)$, we would have

$$\langle lt \rangle = \sum_i a_i \log(x_i) + b_i \log(1 - x_i) \quad (28)$$

and

$$\sigma_{lt}^2 = \sum_i a_i b_i (\log(x_i) - \log(1 - x_i))^2 \quad (29)$$

4 Dynamics: Predictables and Unpredictables

The expected value of the log-normal distribution is extremely chaotic. A small percent of the log-normal distribution, contributes to the majority of the expected value.

Take

$$\frac{N}{2} \exp \left(-\langle lt \rangle s + \frac{\sigma_{lt}^2 s^2}{2} \right) \operatorname{erfc} \left(\frac{-\langle lt \rangle + \sigma_{lt}^2 s + c}{\sqrt{2}\sigma_{lt}} \right) \quad (30)$$

Suppose, the weightset changes from time to time. Knowing w_i , we can successfully estimate σ_{lt} , and $\langle lt \rangle$, from the formulas, in the above section. However generally, estimating c is just as bad as finding the actual c . In fact, c , the value of the term, that contributes the highest probability, holds the key to the correct order of the estimate.

4.1 The Unpredictable 'c'

Suppose, we naively decide to estimate c as by taking

$$\prod_i \max\{1 - x_i, x_i\} \quad (31)$$

Notice that each time, we take the $\max\{1 - x_i, x_i\}$, we would either have $1 - x_i$, or x_i . In the end, we would have a product like $(1 - x_0)(x_1)x_2(1 - x_3)x_4x_5x_5(1 - x_7)(1 - x_8)$. However, for that term, to be the maximum value supplying term, it must be part of the actual function. It is not required to be part of the function. And when it is not in it, it is merely a worst possible bound on the actual maximum, that is part of the function. In general, estimating c , could be an NP-complete process.

5 Fault Detection Analysis

The following analysis is based on an approach by Seth-Agarwal-Farat. We reformulate their method, in terms of vectors that detect those faults, instead of the faults themselves.

Imagine stuck at faults $f_1, f_2, f_3, \dots, f_n$ in the circuit. Each fault is detected by a set of vectors. Suppose, we build a circuit $F_n(\mathbf{X})$, which is 1, when vector \mathbf{X} , detects the fault f_n , otherwise zero. Now, each such circuit for different faults f_n has σ_n , $\langle lt_n \rangle$, and N_n parameters. Now, the probability that a f_n is detected at time instant k , but not before is.

$$\int_0^1 dy N_n \cdot (1 - y)^{k-1} y \cdot p(y, \langle lt_n \rangle, \sigma_n, y_{nmax}) \quad (32)$$

which is same as saying that one of the vectors, that detects f_n , becomes a 1 at time instant k .

Now, the probability that it is detected anytime, upto the time instant k is

$$= \int_0^1 dy N_n [1 + (1-y) + (1-y)^2 + \dots + (1-y)^{k-1}] y \cdot p(y, \langle lt_n \rangle, \sigma_n, y_{nmax}) \quad (33)$$

$$= \int_0^1 dy N_n \left[\frac{(1-y)^k - 1}{1-y-1} \right] y \cdot p(y, \langle lt_n \rangle, \sigma_n, y_{nmax}) \quad (34)$$

$$= \int_0^1 dy N_n [1 - (1-y)^k] p(y, \langle lt_n \rangle, \sigma_n, y_{nmax}) \quad (35)$$

$$= \int_0^1 dy N_n \sum_{i=1}^k (-1)^{i+1} k C_i y^i p(y, \langle lt_n \rangle, \sigma_n, y_{nmax}) \quad (36)$$

$$(37)$$

which is wonderfully the same as,

$$N_n \sum_{i=1}^k (-1)^{i+1} k C_i \Gamma(i, c_n, \langle lt_n \rangle, \sigma_n) \quad (38)$$

Now, suppose $q(N, c, \mu, \sigma)$ is the normalized distribution of N , c , μ , and σ , we would have

$$\int \int \int \int dN dc d\mu d\sigma \sum_{i=1}^k (-1)^{i+1} N q(N, c, \mu, \sigma) k C_i \Gamma(i, c, \mu, \sigma) \quad (39)$$

would give, the probability of faults detected, by iteration k . We shall come back to this expression later. The above expression, should be seen as a mathematical device, which can be used, to prove several properties of fault distribution, fault entropy, etc, in circuits. In fact, based on aprior model of N , c and μ , and σ , one can modify $q(N, c, \mu, \sigma)$ to prove, properties of such models. We shall, in the following sections, use such models, to prove, why increasing input entropy, would increase fault coverage.

One can reformulate this relationship in terms of \mathbf{a} 's and \mathbf{b} 's, and see a direct relationship between input probabilities and fault distribution.

$$\int \int \int \int dN dc da db \sum_{i=1}^k (-1)^{i+1} N q'(N, c, a, b) k C_i \Gamma(i, c, \mu(\mathbf{X}, a, b), \sigma(\mathbf{X}, a, b)) \quad (40)$$

where

$$\mu(\mathbf{X}, a, b) = \sum_i a \log x_i + b \log(1 - x_i) \quad (41)$$

and

$$\sigma^2(\mathbf{X}, a, b) = \sum_i ab (\log x_i - \log(1 - x_i))^2 \quad (42)$$